

Search Notes



Application/Control No.

09/848,101

Examiner

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Applicant(s)/Patent under Reexamination

GRUBER ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	12/05	DN
	26		
703	200		
	201		
	202		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US	12/05	DN
1. PG Pub		1
2. Patent		
II FOREIGN		
1. EPO		
2. JPO		
3. Derwent		
III NPC		
1. Fhxt		
2. Fhxt2		
3. NFhxt		